

## TEST REPORT EN 60269-4

## Low-voltage fuses

## Part 4: Supplementary requirements for fuse-links for the protection of semiconductor devices

Report Number. ....: 03601-A-23D0188-S

Date of issue....: 2024-04-28

Total number of pages .....: 29

Name of Testing Laboratory Suzhou Electrical Apparatus Science Research Institute Co.,

preparing the Report ...... Ltd.(EETI)

Applicant's name ...... Zhejiang Tengen Electric Co., Ltd

Address.....: Sulv Industry Zone, Liushi Town, Yueqing City, Zhejiang

Province, P.R.China.

Test specification:

Standard.....: EN 60269-4:2009, EN 60269-4:2009/AMD1:2012,

EN 60269-4:2009/AMD2:2016

Test procedure .....: CCA Scheme

Non-standard test method .....: N/A

TRF template used ...... IECEE OD-2020-F1:2022, Ed.1.5

Test Report Form No. ..... EN60269\_4D

Test Report Form(s) Originator ....: CQC

Master TRF...... Dated 2023-08-17

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Test item description:	Fuse fo	or protection of semicond	uctor devices	
Trademark(s):	Tenger	ı		
Manufacturer:	,	,	td. n, Yueqing City, Zhejiang Province,	
		TGRS3Z-3ETS, TGRS3Z-3ETM, TGRS3Z-3EQS, TGRS3Z-3EQM		
Ratings: See P		Page 6		
<b>这种</b> 允然			2. 11. 17. 17. 18. 18. 18. 18. 18. 18. 18. 18. 18. 18	
Responsible Testing Laboratory (as applicable), testing procedure and testing location(s):				
		Suzhou Electrical Apparatus Science Research Institute Co., Ltd.(EETI)		
Testing location/ address:		No.7 Yonghe Street, Binhe Road, New District, Suzhou, China		
Tested by (name, function, signature):		Wang Wei (Team leader)	工水	
Approved by (name, function, signature):		Sun Aqin (Supervisor)	7608A	
Testing procedure: CTF Stage 1:			,	
Testing location/ address:				
Tested by (name, function, signature):				
Approved by (name, function, signature):				
☐ Testing procedure: CTF Stage 2:				
Testing location/ address:				
Tested by (name + signature):				
Witnessed by (name, function, signature). :				
Approved by (name, function, signature):				
Testing procedure: CTF Stage 3	3:			
Testing procedure: CTF Stage 4:				
Testing location/ address:				
Tested by (name, function, signature):				
Witnessed by (name, function, signature).:				
Approved by (name, function, signature):				
Supervised by (name, function, signature):				